

Applications Guidance: RH1499MW #447411.1 assembly lot / W19 wafer / W10737593.1 fablot

REF: ELDRS report #08-133, RLAT report #08-134, Radiation Assured Devices. Inc.

Reference ELDRS and RLAT reports found NO doserate sensitivity per TM1019.7 definition, on samples taken from subject fablot, wafer, and assy lot. Both ELDRS and RLAT samples did, however, fail Output High at 1mA and 2.5mA sourcing load at the single-sided +3V supply condition [but passed single-sided +5V supply and double-sided +/- 15V supplies], after 50krads TID.

Investigation into process parameters revealed that NPN and PNP betas on this W19 of fablot W10737593.1 were within process controls but were lower than baseline, so that the output transistors Q15 & Q14 output bias circuitry could not properly drive transistors under loaded conditions after 50krads, with single-sided +3V supply.

Users are advised not to use this wafer or assembly lot with +3V single-sided supply.

